

8M-Bit (1Mx8 /512Kx16) CMOS MASK ROM

FEATURES

- Switchable organization
1,048,576 x 8(byte mode)
524,288 x 16(word mode)
- Fast access time
Random Access : 100ns(Max.)
Page Access : 30ns(Max.)
- 4 Words / 8 bytes page access
- Supply voltage : single +5V
- Current consumption
Operating : 80mA(Max.)
Standby : 50μA(Max.)
- Fully static operation
- All inputs and outputs TTL compatible
- Three state outputs
- Package
-. KM23C8105D(E)T : 44-TSOP2-400

GENERAL DESCRIPTION

The KM23C8105D(E)T is a fully static mask programmable ROM fabricated using silicon gate CMOS process technology, and is organized either as 1,048,576 x 8 bit(byte mode) or as 524,288 x 16 bit(word mode) depending on BHE voltage level.(See mode selection table)

This device includes page read mode function, page read mode allows 4 words (or 8bytes) of data to read fast in the same page, $\overline{CE}$ and $A_2 \sim A_{18}$ should not be changed.

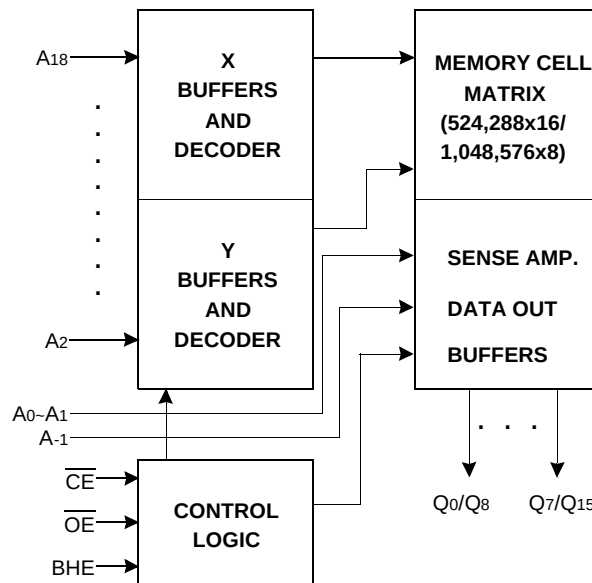
This device operates with a 5V single power supply, and all inputs and outputs are TTL compatible.

Because of its asynchronous operation, it requires no external clock assuring extremely easy operation.

It is suitable for use in program memory of microprocessor, and data memory, character generator.

The KM23C8105D(E)T is packaged in a 44-TSOP2.

FUNCTIONAL BLOCK DIAGRAM

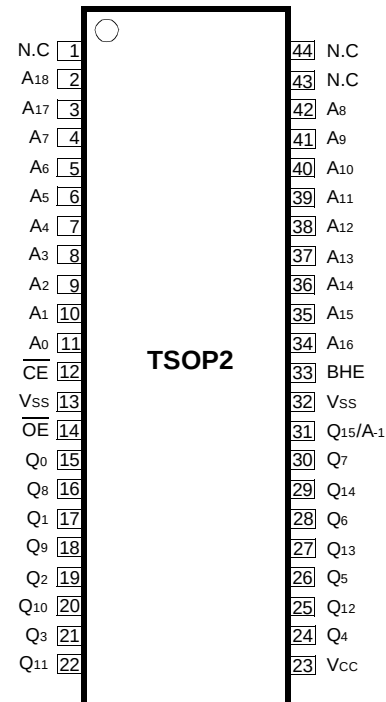


Pin Name	Pin Function
A0 - A1	Page Address Inputs
A2- A18	Address Inputs
Q0 - Q14	Data Outputs
Q15 /A-1	Output 15(Word mode)/ LSB Address(Byte mode)
BHE	Word/Byte selection
$\overline{CE}$	Chip Enable
$\overline{OE}$	Output Enable
Vcc	Power (+5V)
Vss	Ground
N.C	No Connection

PRODUCT INFORMATION

Product	Operating Temp Range	Vcc Range (Typical)	Speed (ns)
KM23C8105DT	0°C~70°C	5.0V	100
KM23C8105DET	-20°C~85°C		

PIN CONFIGURATION



KM23C8105D(E)T

ABSOLUTE MAXIMUM RATINGS

Item	Symbol	Rating	Unit	Remark
Voltage on Any Pin Relative to V _{SS}	V _{IN}	-0.3 to +7.0	V	-
Temperature Under Bias	T _{BIAS}	-10 to +85	°C	-
Storage Temperature	T _{STG}	-55 to +150	°C	-
Operating Temperature	T _A	0 to +70	°C	KM23C8105DT
		-20 to +85	°C	KM23C8105DET

NOTE : Permanent device damage may occur if "ABSOLUTE MAXIMUM RATINGS" are exceeded. Functional operation should be restricted to the conditions as detailed in the operational sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS(Voltage reference to V_{SS}, T_A=0 to 70°C)

Item	Symbol	Min	Typ	Max	Unit
Supply Voltage	V _{CC}	4.5	5.0	5.5	V
Supply Voltage	V _{SS}	0	0	0	V

DC CHARACTERISTICS

Parameter	Symbol	Test Conditions	Min	Max	Unit
Operating Current	I _{CC}	$\overline{CE}=\overline{OE}=V_{IL}$, all outputs open	-	80	mA
Standby Current(TTL)	I _{SB1}	$\overline{CE}=V_{IH}$, all outputs open	-	1	mA
Standby Current(CMOS)	I _{SB2}	$\overline{CE}=V_{CC}$, all outputs open	-	50	μA
Input Leakage Current	I _{LI}	V _{IN} =0 to V _{CC}	-	10	μA
Output Leakage Current	I _{LO}	V _{OUT} =0 to V _{CC}	-	10	μA
Input High Voltage, All Inputs	V _{IH}		2.2	V _{CC} +0.3	V
Input Low Voltage, All Inputs	V _{IL}		-0.3	0.8	V
Output High Voltage Level	V _{OH}	I _{OH} =-400μA	2.4	-	V
Output Low Voltage Level	V _{OL}	I _{OL} =2.1mA	-	0.4	V

NOTE : Minimum DC Voltage(V_{IL}) is -0.3V an input pins. During transitions, this level may undershoot to -2.0V for periods <20ns.
Maximum DC voltage on input pins(V_{IH}) is V_{CC}+0.3V which, during transitions, may overshoot to V_{CC}+2.0V for periods <20ns.

MODE SELECTION

$\overline{CE}$	$\overline{OE}$	BHE	Q _{15/A-1}	Mode	Data	Power
H	X	X	X	Standby	High-Z	Standby
L	H	X	X	Operating	High-Z	Active
L	L	H	Output	Operating	Q ₀ ~Q ₁₅ : Dout	Active
		L	Input	Operating	Q ₀ ~Q ₇ : Dout Q ₈ ~Q ₁₄ : Hi-Z	Active

CAPACITANCE(T_A=25°C, f=1.0MHz)

Item	Symbol	Test Conditions	Min	Max	Unit
Output Capacitance	C _{OUT}	V _{OUT} =0V	-	12	pF
Input Capacitance	C _{IN}	V _{IN} =0V	-	12	pF

NOTE : Capacitance is periodically sampled and not 100% tested.

AC CHARACTERISTICS($T_A=0^{\circ}\text{C}$ to $+70^{\circ}\text{C}$, $V_{CC}=5.0\text{V}\pm 10\%$, unless otherwise noted.)**TEST CONDITIONS**

Item	Value
Input Pulse Levels	0.6V to 2.4V
Input Rise and Fall Times	10ns
Input and Output timing Levels	0.8V and 2.0V
Output Loads	1 TTL Gate and $C_L=100\text{pF}$

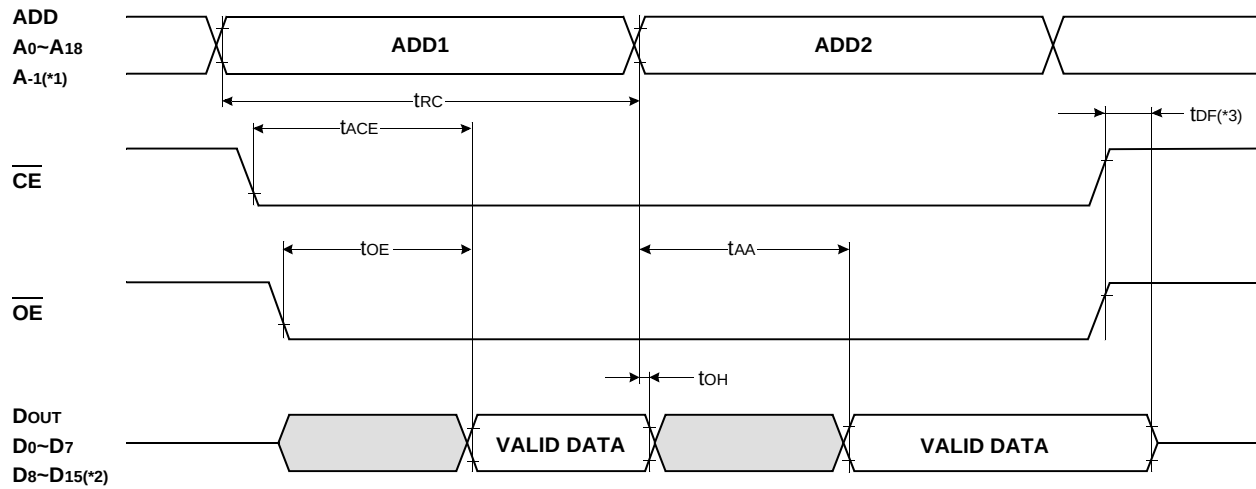
READ CYCLE

Item	Symbol	KM23C8105D(G)-10		KM23C8105D(G)-12		KM23C8105D(G)-15		Unit
		Min	Max	Min	Max	Min	Max	
Read Cycle Time	t_{RC}	100		120		150		ns
Chip Enable Access Time	t_{ACE}		100		120		150	ns
Address Access Time	t_{AA}		100		120		150	ns
Page Address Access Time	t_{PA}		30		50		70	ns
Output Enable Access Time	t_{OE}		30		50		70	ns
Output or Chip Disable to Output High-Z	t_{DF}		20		20		30	ns
Output Hold from Address Change	t_{OH}	0		0		0		ns

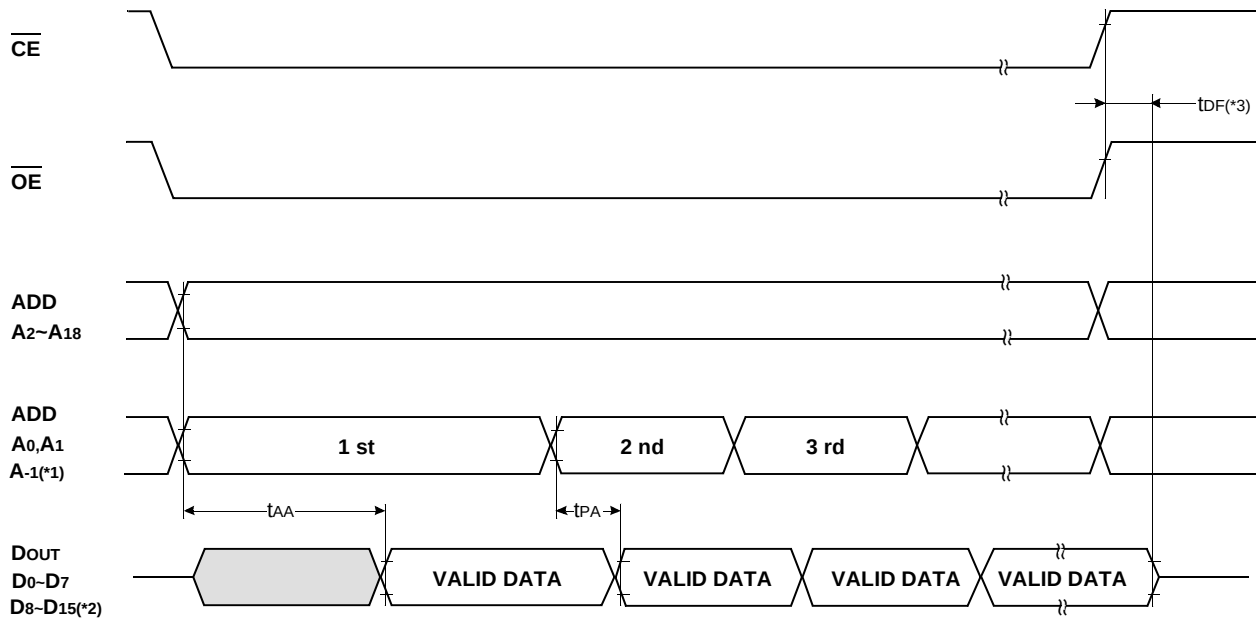
NOTE : Page Address is determined as below.Word mode ($BHE = V_{IH}$) : A_0, A_1 Byte mode ($BHE = V_{IL}$) : A_{-1}, A_0, A_1

TIMING DIAGRAM

READ



PAGE READ



NOTES :

*1. Byte Mode only. A-1 is Least Significant Bit Address.(BHE = V_{IL})

*2. Word Mode only.(BHE = V_{IH})

*3. t_{DF} is defined as the time at which the outputs achieve the open circuit condition and is not referenced to V_{OH} or V_{OL} level.

PACKAGE DIMENSIONS

(Unit : mm/inch)

